

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

dication of

Confirmation No. 8287

Akira FUKUNAGA et al.

Docket No. 2004-0173

Serial No. 10/784,151

Group Art Unit 2812

Filed February 24, 2004

Examiner - Not yet assigned

PLATING APPARATUS AND METHOD OF MANAGING PLATING LIQUID

THE COMMISSIONER IS AUTHORIZED TO CHARGE ANY DEFICIENCY IN THE FEES FOR THIS PAPER TO DEPOSIT

ACCOUNT NO. 23-0975

COMPOSITION

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

Pursuant to the provisions of 37 C.F.R. §§ 1.56, 1.97 and 1.98, Applicants request consideration of the references listed on the attached Form PTO-1449 and any additional information identified below in paragraph 3. A legible copy of each reference listed on the Form PTO-1449 is enclosed, except a copy is not provided for:

| [] | each U.S. Patent and U.S. Patent application publication (for U.S. National |
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| | applications filed after June 30, 2003 and International applications that have |
| | entered U.S. National Stage after June 30, 2003), |
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| [] | each | reference | previously | cited | in | the | international | application |
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| | PCT/_ | | ; and/or | | | | | |

each reference previously cited in prior parent application Serial No. \prod

[X] This Information Disclosure Statement is submitted: la.

within three months of the filing date (or of entry into the National Stage) of the aboveentitled application, or

before the mailing of a first Office Action on the merits or the mailing of a first Office Action after the filing of an RCE,

and thus no certification and/or fee is required.

1b. [] This Information Disclosure Statement is submitted

after the events of above paragraph 1a and prior to the mailing date of a final Office Action or a Notice of Allowance or an action which otherwise closes prosecution in the application, and thus:

- (1) [] the certification of paragraph 2 below is provided, or
- (2) [] the fee of \$180.00 specified in 37 CFR 1.17(p) is enclosed.
- 1c. [] This Information Disclosure Statement is submitted:

after the mailing date of a final Office Action or Notice of Allowance or action which otherwise closes prosecution in the application, and prior to payment of the issue fee, and thus:

the certification of paragraph 2 below is provided, and

the fee of \$180.00 specified in 37 CFR 1.17(p) is enclosed.

- 2. It is hereby certified
 - a. [] that each item of information contained in this Information Disclosure Statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of the Statement, or
 - b. [] that no item of information contained in the Information Disclosure Statement was cited in a communication from a foreign patent office in a counterpart foreign application and, to the knowledge of the person signing the certification after making reasonable inquiry, was known to any individual designated in §1.56(c) more than three months prior to the filing of the Statement.

- 3. [] Consideration of the following list of additional information (including any copending or abandoned U.S. application, prior uses and/or sales, etc.) is requested.
- 4. For each non-English language reference listed on the attached form PTO-1449, reference is made to:
 - a. [] a full or partial English language translation submitted herewith,
 - b. **X** a foreign patent office search report (in the English language) submitted herewith,
 - c. [] the concise explanation contained in the specification of the present application at page,
 - d. [] the concise explanation set forth in the attached English language abstract,
 - e. [] the concise explanation set forth below or on a separate sheet attached to the reference:
- 5. [X] A foreign patent office search report citing one or more of the references is enclosed.

Respectfully submitted,

Akira FUKUNAGA

W. Douglas Hahm

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WDH/ksh

Washington, D.C. 20006-1021

Telephone: 202-721-8200 Facsimile: 202-721-8250

July 30, 2004

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